AN5015K

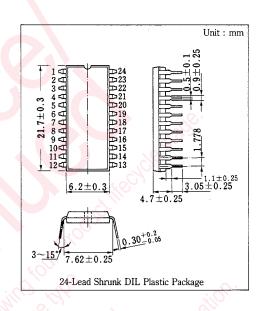
TV Electronic Channel Selection Circuit

Outline

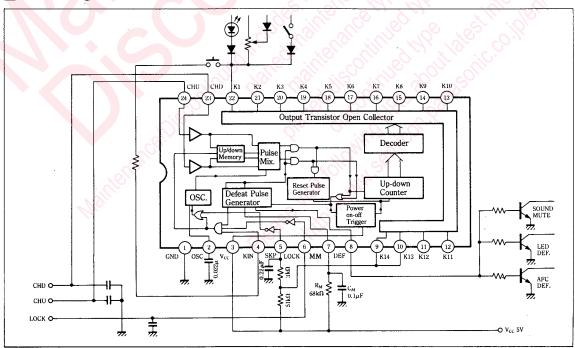
The AN5015K is an integrated circuit designed for electronic tuner by the preset volume method.

Features

- Can drive LED directly (Vsat=75mV typ., I_K=15mA)
- Capable of tuning 14 channels
- Channel lock is possible
- Defeat pulse width can be adjusted by external C. R.
- Low power consumption (V_{cc}=5V, I_{cc}=15mA typ.)
- Breakdown voltage of output terminal: 50V
- Skip channel selection possible



Block Diagram



■ Pin

Pin No.	Pin Name	Pin No.	Pin Name
1	GND	13	Selection Output (K10)
2	OSC	14	Selection Output (K9)
3	V _{cc}	15	Selection Output (K8)
4	K-input	16	Selection Output (K7)
5	Skip	17	Selection Output (K6)
6	Channel Lock	18	Selection Output (K5)
7	Mon-multi	19	Selection Output (K4)
8	Defeat Output	20	Selection Output (K3)
9	Selection Output (K14)	21	Selection Output (K2)
10	Selection Output (K13)	22	Selection Output (K1)
11	Selection Output (K12)	23	Channel Down
12	Selection Output (K11)	24	Channel Up

■ Absolute Maximum Ratings (Ta=25°C)

Item	Symbol	Rating	Unit					
Supply Voltage	$V_{cc(v_3-1)}$	6	V					
	V_{2-1}	0 ~Vcc	V					
Torminal Voltage	V _{.6-1}	0 ∼V _{cc}	v					
Terminar Voltage	$V_{23,24-1}$	0 ∼V _{cc}	V					
	$V_{9\sim22-1}$	0 ~V _{cc}	V					
Supply Current	Icc	22	mA					
	I_4	0 ~ 5	mA					
	${ m I_5}$	0 ~ 5	mA (C)					
Supply Voltage Terminal Voltage Supply Current Operating Ambient Temperature	$I_{9\sim22}$	0 ~ 30	mA mA					
	I_8	$-5\sim 0$	mA					
	P _D *	150	mW					
Operating Ambient Temperature	Topr	-20~+70	S S C					
Storage Temperature	$T_{ m sig}$	-55~+150	(0)					

^{*}The allowable range shall be up to 525 mW instantaneously when channels are switched.

Electrical Characteristics (Ta=25°C)

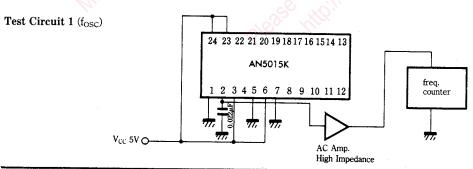
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Supply Current	I _{tot} *		$V_{cc}=5V$	11.25	15	18.25	mΑ
Tuning Output	V _{OL(K)} *		$V_{cc}=4V$, $I_{ot}=15mA$			150	mV
Saturation Voltage	V OL(K)		V cc — 4 V , IoL — I 3111 A			150	III V
Tuning Output	ĭ *		N -4N N -50N			_	
Leak Current	$I_{OH(K)}*$		$V_{cc}=4V$, $V_{OH}=50V$			5	μΑ
Tuning Output	BVo*		37 437 T 10 . A	50			
Breakdown Voltage	DVO.		$V_{cc} = 4V$, $I_{OH(K)} = 10 \ \mu \ A$	- 50			V
DEF Output Voltage	V _{OH(D)} *	. 60-	$V_{cc}=5V$, $I_{OH}=-5mA$	1	3	4	V
CHU/D High			37 537	0.0			
Threshold Voltage	$V_{\text{TH(CH)}}*$		$V_{cc}=5V$	2.6	3.3	4.0	V
CHU/D Low	3.7 ±		37 237				
Threshold Voltage	$V_{\scriptscriptstyle \mathrm{TL(CH)}}*$		$V_{cc}=5V$	1.1	1.4	1.7	V
CHU/D Input Current	I _{IH(CH)} *		$V_{cc}=5V, V_{23,24}=4V$	50		450	μΑ
CHU/D Leak Current	I _{IL(CH)} *		$V_{cc}=5V$, $V_{iL}=0V$	- 5			μΑ
KIN Input Current	I _{IH(KI)} *		V _{cc} =5V	200			μΑ
KIN Leak Current	I _{IL(KI)} *		$V_{cc}=5V$, $V_{iL}=0V$	– 5			μΑ
SKP Input Current	I _{IH(SK)} *		$V_{cc}=5V$	50			μΑ
SKP Leak Current	I ^{™(SK)} *		$V_{cc}=5V$, $V_{iL}=0V$	- 5			μΑ

■ Electrical Characteristics (Cont'd) (Ta=25°C)

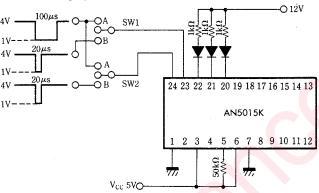
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit	
CH Lock Input Current	I _{IH(LO)} *		V _{cc} =5V·	50			μА	
CH Lock Leak Current	I _{IL(LO)} *		$V_{cc}=5V$, $V_{iL}=0V$	- 5			μΑ	
OSC.Input Current (1)	I _{IH(OS)} *		$V_{cc}=4V$, $V_{IH}=3V$	50	70	90	μА	
OSC.Input Current (2)	I _{IL(OS)} *		$V_{cc}=6V$, $V_{IL}=1V$	-170	-120	- 90	μΑ	
Clock Oscillation Frequency	f _{osc}	1	$V_{cc} = 5V$, $C = 0.022 \mu F$	1.2	1.7	2.2	KHz	
CH.Up/Down Pulse Width	τ 1	2	V _{cc} =5V			20	μs	
Initializing Pulse Width	τ 2	2	V _{cc} =5V		300	100	μ s	
DEF Output Pulse Width	toer	3	$V_{cc} = 5V, R = \frac{50}{2} k\Omega, C = 0.1 \mu F$	2.5	3.4	4.5	ms	

*Test Conditions

Item	Symbol	Test Pir	est Pin Pin No.											111													
rtem	Symbol	No.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	Not
Supply Voltage	Icc	I ₃	OV		57		50kΩ to3	57	07								5	D	Г			İ			57	57	
Tuning Output Saturation Voltage	V _{OL(R)}	V ₂₂	OV		4V		50kΩ 10.3	to.	OV						3	S,	0							3.3kΩ 50\	-	to	For R:1ch
Tuning Output Leak Current	I _{OH(R)}	I ₂₂	OV		40		50kΩ to3	to ③	ov					40	3		3							100kΩ 50V	to 3	to 3	For R:1ch
Tuning Output Breakdown Voltage	BVo	V ₂₂	0V		4V		50kΩ to3	3	ov			0		, <u>, , , , , , , , , , , , , , , , , , </u>	S	37								100kΩ 50V	to 4V ③	to 4V	For R:1ch
DEF Output Voltage	V _{OH(D)}	V ₈	OV		57		50kΩ to3	3	OV	9	0		o			7)	_	8						10kΩ to(3)	OV	
CHU/D High Threshold Voltage	V _{TH(CH)}	V _{23,24} *1	ov		5V		50kΩ to3	to 3	0.5 V	25		16			S	7	6,	3							to ③		
CHU/D Low Threshold Voltage	V _{TL(CH)}	V _{23,24} *2	ov		57		50kΩ to3	to 3	0.5 V	ď	(0)	. 0	6				<u> </u>	4	50	1	<u>je</u>	9	S).\\	to ③		
CHU/D Input Current	I _{IH(CH)}	I23,24	OV		57	0	50kΩ to3		0	7	. (۰0			20				4				4V	4V	
CHU/D Leak Current	I _{IL(CH)}	V _{23,24}	OV		57	1	50kΩ to.3	2			0		: (9	5		7		X	9		0				10kΩ	10kΩ	<u> </u>
KIN Input Current	I _{IH(KI)}	I ₇	OV	17	57	400 mA	50kΩ to3	OV	02			X	<i>),</i>					0		~?	7	-			0\' 10 3	0V 10	
KIN Leak Current	I _{IL(KI)}	I ₄	0٧	17	57	OV	50kΩ to3	OV	0.5 V		~	3		CS					~?						to ③	10	
SKIP Input Current	I _{IH(SK)}	I ₇	OV	1٧	5V	OV	50 mA	10 (3)	0.5 V		8			9		V		0	1						10	to 3	
SKIP Leak Current	I _{IL(SK)}	I ₅	OV	17	57	OV	OV	(3)	0.5 V	6							C	9			_				10	to ③	
CH.Lock Input Current	I _{IH(LO)}	I ₇	OV	OV	17	10kΩ to3	50kΩ to3	50 mA	0.5 V				< 0	12		3	1								to ③	to ③	
CH.Lock Leak Current	I _{IL(LO)}	I ₆	07	17	57	10kΩ to 3	50kΩ to3	07	0.5 V			C	11	-	Q	50									10	to ③	
OSC.Input Current	In(os)	I ₂	OV	37	4V		OV	3			•			2	19				-						to ③	to ③	
OSC.Input Current	IIL(OS)	I ₂	07	17	6V		٥٧	10 ③			16		(3)	12		T								\neg	to ③	10	



Test Circuit 2 (τ_1, τ_2)



① SW1 and SW2 at the side A are initialized in a pulse of $100 \mu s$.

("Initial Operation" in this case denotes that 1 channel is output when CHU and CHD become Low level at the same time.)

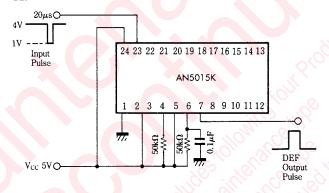
②SW1 at the side B is in CHD operation in a pulse of 20 μ s.

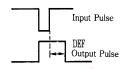
("CHD operation" in this case denotes that a channel is Down when CHD becomes Low level.)

(3) SW2 at the side B is in CHU operation in a pulse of 20 μ s.

("CHU operation" in this case denotes that a channel is Up when CHU becomes Low level.)

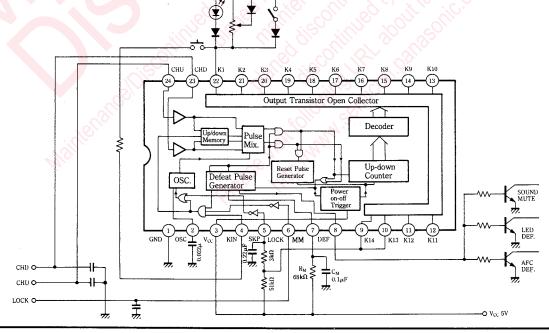
Test Circuit 3 (τ_{DEF})





Note: Measure the time from the end of input pulse to the end of DEF output pulse.

Application Circuit



Request for your special attention and precautions in using the technical information and semiconductors described in this book

- (1) If any of the products or technical information described in this book is to be exported or provided to non-residents, the laws and regulations of the exporting country, especially, those with regard to security export control, must be observed.
- (2) The technical information described in this book is intended only to show the main characteristics and application circuit examples of the products. No license is granted in and to any intellectual property right or other right owned by Panasonic Corporation or any other company. Therefore, no responsibility is assumed by our company as to the infringement upon any such right owned by any other company which may arise as a result of the use of technical information described in this book.
- (3) The products described in this book are intended to be used for standard applications or general electronic equipment (such as office equipment, communications equipment, measuring instruments and household appliances).
 - Consult our sales staff in advance for information on the following applications:
 - Special applications (such as for airplanes, aerospace, automobiles, traffic control equipment, combustion equipment, life support systems and safety devices) in which exceptional quality and reliability are required, or if the failure or malfunction of the products may directly jeopardize life or harm the human body.
 - · Any applications other than the standard applications intended.
- (4) The products and product specifications described in this book are subject to change without notice for modification and/or improvement. At the final stage of your design, purchasing, or use of the products, therefore, ask for the most up-to-date Product Standards in advance to make sure that the latest specifications satisfy your requirements.
- (5) When designing your equipment, comply with the range of absolute maximum rating and the guaranteed operating conditions (operating power supply voltage and operating environment etc.). Especially, please be careful not to exceed the range of absolute maximum rating on the transient state, such as power-on, power-off and mode-switching. Otherwise, we will not be liable for any defect which may arise later in your equipment.
- Even when the products are used within the guaranteed values, take into the consideration of incidence of break down and failure mode, possible to occur to semiconductor products. Measures on the systems such as redundant design, arresting the spread of fire or preventing glitch are recommended in order to prevent physical injury, fire, social damages, for example, by using the products.
- (6) Comply with the instructions for use in order to prevent breakdown and characteristics change due to external factors (ESD, EOS, thermal stress and mechanical stress) at the time of handling, mounting or at customer's process. When using products for which damp-proof packing is required, satisfy the conditions, such as shelf life and the elapsed time since first opening the packages.
- (7) This book may be not reprinted or reproduced whether wholly or partially, without the prior written permission of our company.

20080805